

# **PARTIAL GOOD INTEGRATED CIRCUIT AND METHOD OF TESTING SAME**

## **ABSTRACT**

An integrated circuit, including: a multiplicity of macro-circuits, each macro-  
5 circuit having the same function; a fuse bank containing a multiplicity of fuses, the state  
of the fuses storing test data indicating at least which macro-circuits failed a test; and  
means for preventing utilization of failing macro-circuits during operation of the  
integrated circuit and a method generating a partial good integrated circuit, the method  
including: providing an integrated circuit have a multiplicity of macro-circuits arranged in  
10 one or more groups, each macro-circuit having the same function and a fuse bank  
containing fuses; testing each macro-circuit prior to a fuse programming operation;  
programming the fuses in the fuse bank in order to store data indicating at least which  
macro-circuits failed the testing step; and preventing utilization of each failing macro-  
circuit during operation of the integrated based on the data stored in the fuse bank.